

February 2008

Motion-SPM[™]

FSBB30CH60C Smart Power Module

Features

- UL Certified No.E209204(SPM27-EC package)
- · Very low thermal resistance due to using DBC
- · Easy PCB layout due to built in bootstrap diode
- 600V-30A 3-phase IGBT inverter bridge including control ICs for gate driving and protection
- Divided negative dc-link terminals for inverter current sensing applications
- · Single-grounded power supply due to built-in HVIC
- Isolation rating of 2500Vrms/min.

Applications

- AC 100V ~ 253V three-phase inverter drive for small power ac motor drives
- Home appliances applications like air conditioner and washing machine

General Description

It is an advanced motion-smart power module (Motion-SPMTM) that Fairchild has newly developed and designed to provide very compact and high performance ac motor drives mainly targeting low-power inverter-driven application like air conditioner and washing machine. It combines optimized circuit protection and drive matched to low-loss IGBTs. System reliability is further enhanced by the integrated under-voltage lock-out and short-circuit protection. The high speed built-in HVIC provides opto-coupler-less single-supply IGBT gate driving capability that further reduce the overall size of the inverter system design. Each phase current of inverter can be monitored separately due to the divided negative dc terminals.

Top View Bottom View 44mm 26.8mm Figure 1.

Integrated Power Functions

• 600V-30A IGBT inverter for three-phase DC/ACpower conversion (Please refer to Figure 3)

Integrated Drive, Protection and System Control Functions

- For inverter high-side IGBTs: Gate drive dicuit, High voltage isolated high-speed level shifting
 Control circuit under-voltage (UV) protection
 Note) Available bootstrap circuit example is given in Figures 12 and 13.
- For inverter low-side IGBTs: Gate dive circuit, Short circuit protection (SC)
 Control supply circuit under-voltage (UV) protection
- Fault signaling: Corresponding toUV (Low-side supply) and SC faults
- Input interface: 3.3/5V CMOS/LSTTL compatible, Schmitt trigger input

Pin Configuration

Top View

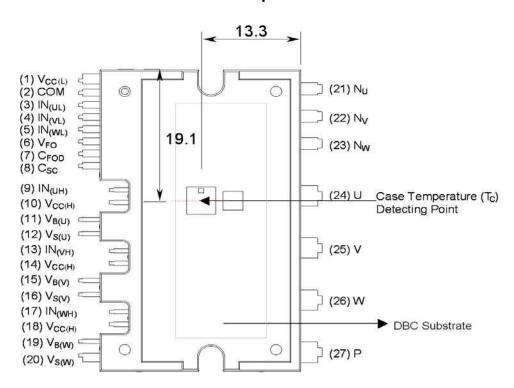
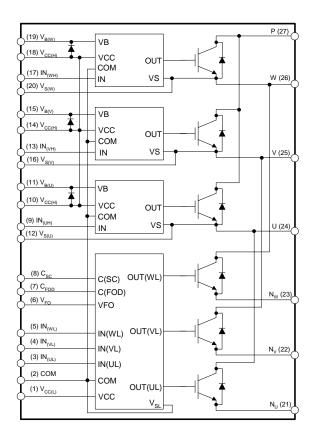


Figure 2.

Pin Descriptions

1 V _{CC(L)} Low-side Common Bias Voltage for IC and IGBTs Driving 2 COM Common Supply Ground 3 IN _(UL) Signal Input for Low-side U Phase 4 IN _(VL) Signal Input for Low-side V Phase 5 IN _(WL) Signal Input for Low-side W Phase 6 V _{FO} Fault Output 7 C _{FOD} Capacitor for Fault Output Duration Time Selection 8 C _{SC} Capacitor (Low-pass Filter) for Short-Current Detection Input 9 IN _(UH) Signal Input for High-side U Phase 10 V _{CC(H)} High-side Common Bias Voltage for IC and IGBTs Driving 11 V _{B(U)} High-side Bias Voltage Ground for U Phase IGBT Driving 12 V _{S(U)} High-side Bias Voltage Ground for U Phase IGBT Driving 13 IN _(VH) Signal Input for High-side V Phase 14 V _{CC(H)} High-side Common Bias Voltage for IC and IGBTs Driving 15 V _{B(V)} High-side Bias Voltage for V Phase IGBT Driving 16 V _{S(V)} High-side Bias Voltage Ground for V Phase IGBT Driving	
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16 V _{S(V)} High-side Bias Voltage Ground for V Phase IGBT Driving	
17 IN _(WH) Signal Input for High-side W Phase	
18 V _{CC(H)} High-side Common Bias Voltage for IC and IGBTs Driving	
19 V _{B(W)} High-side Bias Voltage for W Phase IGBT Driving	
20 V _{S(W)} High-side Bias Voltage Ground for W Phase IGBT Driving	
21 N _U Negative DC-Link Input for U Phase	
22 N _V Negative DC–Link Input for V Phase	
23 N _W Negative DC–Link Input for W Phase	
24 U Output for U Phase	
25 V Output for V Phase	
26 W Output for W Phase	
27 P Positive DC-Link Input	

Internal Equivalent Circuit and Input/Output Pins



Note

- 1. Inverter low-side is composed of three IGBTs, freewheeling diodes for each IGBT and one control IC. It has gate drive and protection functions.
- 2. Inverter power side is composed of four inverter dc-link input terminals and three inverter output terminals.
- 3. Inverter high-side is composed of three IGBTs, freewheeling diodes and three drive ICs for each IGBT.

Figure 3.

Absolute Maximum Ratings ($T_J = 25$ °C, Unless Otherwise Specified)

Inverter Part

Symbol	Parameter	Conditions	Rating	Units
V _{PN}	Supply Voltage	Applied between P- N _U , N _V , N _W	450	V
V _{PN(Surge)}	Supply Voltage (Surge)	Applied between P- N _U , N _V , N _W	500	V
V _{CES}	Collector-emitter Voltage		600	V
± I _C	Each IGBT Collector Current	T _C = 25℃	30	Α
± I _{CP}	Each IGBT Collector Current (Peak)	T _C = 25℃, Under 1ms Pulse Width	60	Α
P _C	Collector Dissipation	T _C = 25℃ per One Chip	106	W
TJ	Operating Junction Temperature	(Note 1)	-40 ~ 150	C

Note

Control Part

Symbol	mbol Parameter Conditions		Rating	Units
V _{CC}	Control Supply Voltage	Applied between V _{CC(H)} , V _{CC(L)} - COM	20	V
V _{BS}	High-side Control Bias Voltage	Applied between $V_{B(U)}$ - $V_{S(U)}$, $V_{B(V)}$ - $V_{S(V)}$		V
V _{IN}	Input Signal Voltage	$ \begin{array}{cccccccccccccccccccccccccccccccccccc$	-0.3~17	V
V _{FO}	Fault Output Supply Voltage	Applied between V _{FO} - COM	-0.3~V _{CC} +0.3	V
I _{FO}	Fault Output Current	ut Current Sink Current at V _{FO} Pin		mA
V _{SC}	Current Sensing Input Voltage	Applied between C _{SC} - COM	-0.3~V _{CC} +0.3	V

Bootstrap Diode Part

Symbol Parameter		Conditions	Rating	Units
V _{RRM} Maximum Repetitive Reverse Voltage			600	V
I _F	Forward Current	T _C = 25℃	0.5	Α
I _{FP}	Forward Current (Peak)	T _C = 25℃, Under 1ms Pulse Width	2	Α
T_J	Operating Junction Temperature		-40 ~ 150	C

Total System

Symbol	mbol Parameter Conditions		Rating	Units
V _{PN(PROT)}	Self Protection Supply Voltage Limit (Short Circuit Protection Capability)	117 0 00 00		V
T _C	Module Case Operation Temperature	-40°C≤ T _J ≤ 150°C, See Figure 2	-40 ~ 125	C
T _{STG}	Storage Temperature		-40 ~ 150	C
V _{ISO}	Isolation Voltage	60Hz, Sinusoidal, AC 1 minute, Connection Pins to heat sink plate	2500	V _{rms}

Thermal Resistance

Symbol Parameter		Conditions	Min.	Тур.	Max.	Units
R _{th(j-c)Q}	Junction to Case Thermal	Inverter IGBT part (per 1/6 module)	-	-	1.17	€\M
R _{th(j-c)F}	Resistance	Inverter FWD part (per 1/6 module)	-	-	1.87	€/W

Note:

^{1.} The maximum junction temperature rating of the power chips integrated within the SPM is $150^{\circ}C(@T_{C} \le 125^{\circ}C)$.

^{2.} For the measurement point of case temperature($T_{\mbox{\scriptsize C}}$), please refer to Figure 2.

$\textbf{Electrical Characteristics} \ \, (\textbf{T}_{J} = 25\%, \, \textbf{Unless Otherwise Specified})$

Inverter Part

S	Symbol Paramete		Condi	tions	Min.	Тур.	Max.	Units
V	CE(SAT)	Collector-Emitter Saturation Voltage	$V_{CC} = V_{BS} = 15V$ $V_{IN} = 5V$	I _C = 20A, T _J = 25℃	-	-	2.0	V
	V _F	FWD Forward Voltage	V _{IN} = 0V	I _F = 20A, T _J = 25℃	-	-	2.1	V
HS	t _{ON}	Switching Times	$V_{PN} = 300V, V_{CC} = V_{BS}$	_S = 15V	-	0.75	-	μS
	t _{C(ON)}		$I_C = 30A$	ve I nad	-	0.2	-	μS
	t _{OFF}		(Note 3)	$V_{IN} = 0V \leftrightarrow 5V$, Inductive Load (Note 3)		0.4	-	μS
	t _{C(OFF)}					0.1	-	μS
	t _{rr}				-	0.1	-	μS
LS	t _{ON}		$V_{PN} = 300V, V_{CC} = V_{BS}$	_S = 15V	-	0.55	-	μS
	t _{C(ON)}		$I_C = 30A$ $V_{IN} = 0V \leftrightarrow 5V$, Inducti	ve I nad	-	0.35	-	μS
	t _{OFF}		(Note 3)	ve Load	-	0.4	-	μS
	t _{C(OFF)}			,		0.1	-	μS
	t _{rr}				-	0.1	-	μS
	I _{CES}	Collector-Emitter Leakage Current	$V_{CE} = V_{CES}$		-	-	1	mA

Note

Control Part

Symbol	Parameter	Co	nditions	Min.	Тур.	Max.	Units
I _{QCCL}	Quiescent V _{CC} Supply Current	V _{CC} = 15V IN _(UL, VL, WL) = 0V	V _{CC(L)} - COM	ı	-	23	mA
I _{QCCH}		V _{CC} = 15V IN _(UH, VH, WH) = 0V	V _{CC(H)} - COM	i	-	600	μА
I_{QBS}	Quiescent V _{BS} Supply Current	$V_{BS} = 15V$ $IN_{(UH, VH, WH)} = 0V$	$oxed{ V_{B(U)} - V_{S(U)}, V_{B(V)} - V_{S(V)}, \ V_{B(W)} - V_{S(W)} }$	i	-	500	μА
V_{FOH}	Fault Output Voltage	V _{SC} = 0V, V _{FO} Circu	it: 4.7kΩ to 5V Pull-up	4.5	-	-	V
V_{FOL}		V _{SC} = 1V, V _{FO} Circu	it: 4.7kΩ to 5V Pull-up	-	-	0.8	V
V _{SC(ref)}	Short Circuit Trip Level	V _{CC} = 15V (Note 4)	V _{CC} = 15V (Note 4)		0.5	0.55	V
TSD	Over-temperature protection	Temperature at LVIC	Temperature at LVIC		160	-	S.
ΔTSD	Over-temperature protection hysterisis	Temperature at LVIC	;	-	5	-	C
UV _{CCD}	Supply Circuit Under-	Detection Level		10.7	11.9	13.0	V
UV _{CCR}	Voltage Protection	Reset Level		11.2	12.4	13.4	V
UV _{BSD}		Detection Level		10	11	12	V
UV _{BSR}		Reset Level		10.5	11.5	12.5	V
t _{FOD}	Fault-out Pulse Width	C _{FOD} = 33nF (Note 5)		1.0	1.8	-	ms
V _{IN(ON)}	ON Threshold Voltage	Applied between $IN_{(UH)}$, $IN_{(VH)}$, $IN_{(WH)}$, $IN_{(UL)}$, $IN_{(VL)}$, $IN_{(WL)}$ - COM		2.8	-	-	V
V _{IN(OFF)}	OFF Threshold Voltage			-	-	0.8	V

Note:

^{3.} t_{ON} and t_{OFF} include the propagation delay time of the internal drive IC. $t_{C(ON)}$ and $t_{C(OFF)}$ are the switching time of IGBT itself under the given gate driving condition internally. For the detailed information, please see Figure 4.

^{4.} Short-circuit current protection is functioning only at the low-sides.

^{5.} The fault-out pulse width t_{FOD} depends on the capacitance value of C_{FOD} according to the following approximate equation: $C_{FOD} = 18.3 \times 10^{-6} \times t_{FOD}[F]$

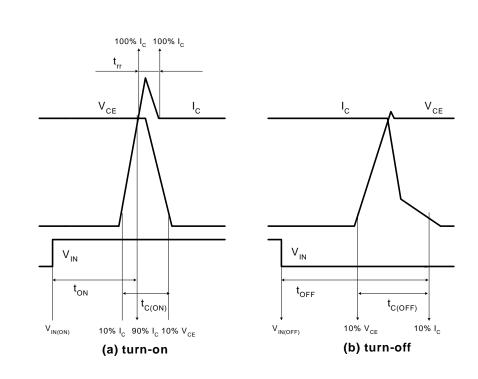


Figure 4. Switching Time Definition

Switching Loss (Typical)

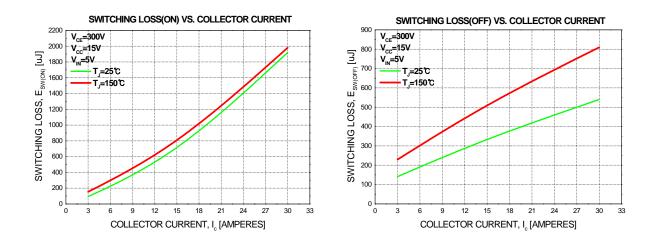
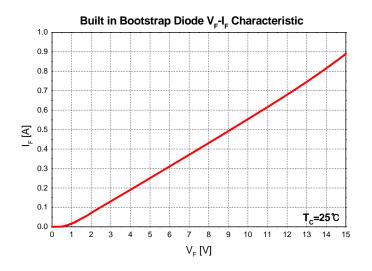


Figure 5. Switching Loss Characteristics

Bootstrap Diode Part

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Units
V _F	Forward Voltage	I _F = 0.1A, T _C = 25℃	-	2.5	-	V
t _{rr}	Reverse Recovery Time	I _F = 0.1A, T _C = 25℃	-	80	-	ns



Note:

6. Built in bootstrap diode includes around 15 Ω resistance characteristic.

Figure 6. Built in Bootstrap Diode Characteristics

Recommended Operating Conditions

Symbol	Parameter	Conditions	Value			Units
Symbol	raiailletei	Conditions	Min.	Тур.	Max.	Units
V _{PN}	Supply Voltage	Applied between P - N _U , N _V , N _W	-	300	400	V
V _{CC}	Control Supply Voltage	Applied between V _{CC(H)} , V _{CC(L)} - COM	13.5	15	16.5	V
V _{BS}	High-side Bias Voltage	Applied between $V_{B(U)}$ - $V_{S(U)}$, $V_{B(V)}$ - $V_{S(V)}$, $V_{B(W)}$ - $V_{S(W)}$	13.0	15	18.5	V
dV _{CC} /dt, dV _{BS} /dt	Control supply variation		-1	-	1	V/μs
t _{dead}	Blanking Time for Preventing Arm-short	For Each Input Signal	2.0	-	-	μS
f _{PWM}	PWM Input Signal	$-40^{\circ}C \le T_C \le 125^{\circ}C$, $-40^{\circ}C \le T_J \le 150^{\circ}C$	-	-	20	kHz
V _{SEN}	Voltage for Current Sensing	Applied between N _U , N _V , N _W - COM (Including surge voltage)	-4		4	V

Mechanical Characteristics and Ratings

Parameter	Col	nditions		Limits		Units
raiailletei	Col	Conditions		Тур.	Max.	Ullits
Mounting Torque	Mounting Screw: - M3	Recommended 0.62N• m	0.51	0.62	0.80	N• m
Device Flatness		Note Figure 5	0	-	+120	μm
Weight			-	15.00	-	g

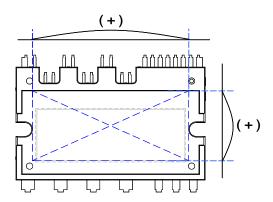
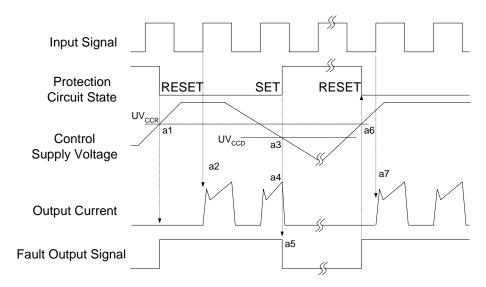


Figure 7. Flatness Measurement Position

Package Marking and Ordering Information

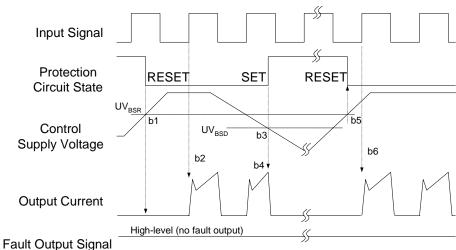
Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FSBB30CH60C	FSBB30CH60C	SPM27-EC	-	=	10

Time Charts of SPMs Protective Function



- a1 : Control supply voltage rises: After the voltage rises UV_{CCR} , the circuits start to operate when next input is applied.
- a2: Normal operation: IGBT ON and carrying current.
- a3 : Under voltage detection (UV_{CCD}).
- a4: IGBT OFF in spite of control input condition.
- a5 : Fault output operation starts.
- a6 : Under voltage reset (UV $_{CCR}$).
- a7: Normal operation: IGBT ON and carrying current.

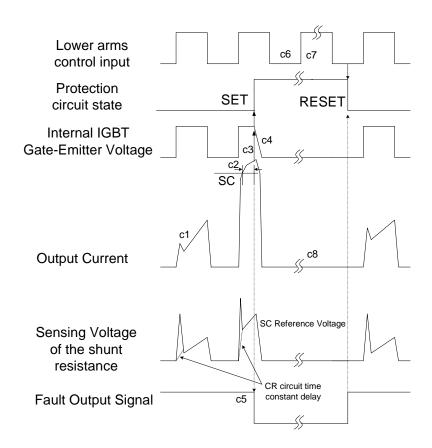
Figure 8. Under-Voltage Protection (Low-side)



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- b1 : Control supply voltage rises: After the voltage reaches UV_{BSR}, the circuits start to operate when next input is applied.
- b2: Normal operation: IGBT ON and carrying current.
- b3: Under voltage detection (UV_{BSD}).
- b4: IGBT OFF in spite of control input condition, but there is no fault output signal.
- b5 : Under voltage reset (UV_{BSR})
- b6: Normal operation: IGBT ON and carrying current

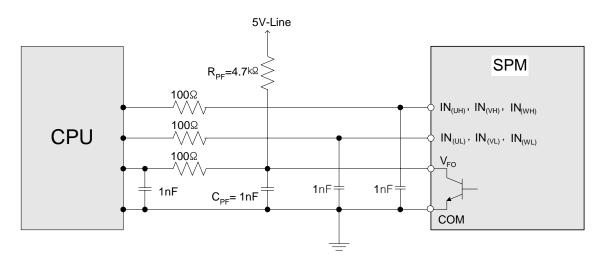
Figure 9. Under-Voltage Protection (High-side)



(with the external shunt resistance and CR connection)

- c1: Normal operation: IGBT ON and carrying current.
- c2 : Short circuit current detection (SC trigger).
- c3: Hard IGBT gate interrupt.
- c4: IGBT turns OFF.
- c5 : Fault output timer operation starts: The pulse width of the fault output signal is set by the external capacitor C_{FO} .
- c6: Input "L": IGBT OFF state.
- c7 : Input "H": IGBT ON state, but during the active period of fault output the IGBT doesn't turn ON.
- c8: IGBT OFF state

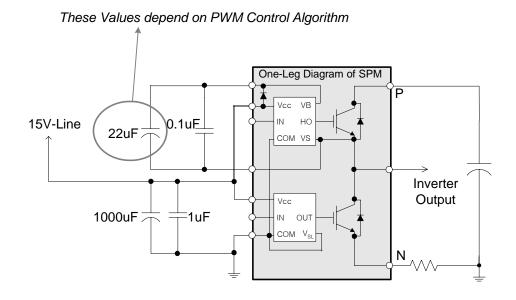
Figure 10. Short-Circuit Current Protection (Low-side Operation only)



Note:

- 1) RC coupling at each input might change depending on the PWM control scheme used in the application and the wiring impedance of the application's printed circuit board. The SPM input signal section integrates 5kΩ (typ.) pull-down resistor. Therefore, when using an external filtering resistor, please pay attention to the signal voltage drop at input terminal.
- 2) The logic input is compatible with standard CMOS or LSTTL outputs.

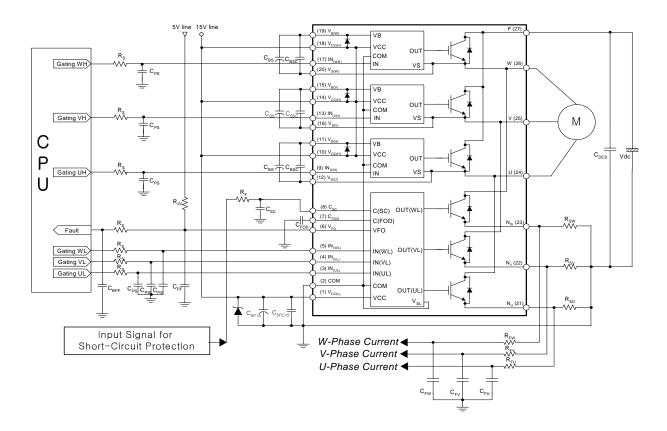
Figure 11. Recommended CPU I/O Interface Circuit



Note:

1) The ceramic capacitor placed between V_{CC}-COM should be over 1uF and mounted as close to the pins of the SPM as possible.

Figure 12. Recommended Bootstrap Operation Circuit and Parameters

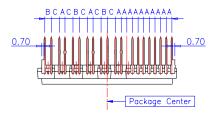


Note:

- 1) To avoid malfunction, the wiring of each input should be as short as possible. (less than 2-3cm)
- 2) By virtue of integrating an application specific type HVIC inside the SPM, direct coupling to CPU terminals without any opto-coupler or transformer isolation is possible.
- 3) V_{FO} output is open collector type. This signal line should be pulled up to the positive side of the 5V power supply with approximately 4.7kΩ resistance. Please refer to Figure11.
- 4) C_{SP15} of around 7 times larger than bootstrap capacitor C_{BS} is recommended.
- 5) V_{FO} output pulse width should be determined by connecting an external capacitor(C_{FOD}) between C_{FOD} (pin7) and COM(pin2). (Example : if C_{FOD} = 33 nF, then t_{FO} = 1.8ms (typ.)) Please refer to the note 5 for calculation method.
- 6) Input signal is High-Active type. There is a 5kΩ resistor inside the IC to pull down each input signal line to GND. RC coupling circuits should be adopted for the prevention of input signal oscillation. R_SC_{PS} time constant should be selected in the range 50~150ns. C_{PS} should not be less than 1nF.(Recommended R_S=100Ω, C_{PS}=1nF)
- 7) To prevent errors of the protection function, the wiring around R_F and C_{SC} should be as short as possible.
- 8) In the short-circuit protection circuit, please select the $R_F C_{SC}$ time constant in the range 1.5~2 μ s.
- 9) Each capacitor should be mounted as close to the pins of the SPM as possible.
- 10) To prevent surge destruction, the wiring between the smoothing capacitor and the P&GND pins should be as short as possible. The use of a high frequency non-inductive capacitor of around 0.1~0.22µF between the P&GND pins is recommended.
- 11) Relays are used at almost every systems of electrical equipments of home appliances. In these cases, there should be sufficient distance between the CPU and the relays.
- 12) $C_{\mbox{\footnotesize SPC15}}$ should be over $1\mu\mbox{\footnotesize F}$ and mounted as close to the pins of the SPM as possible.

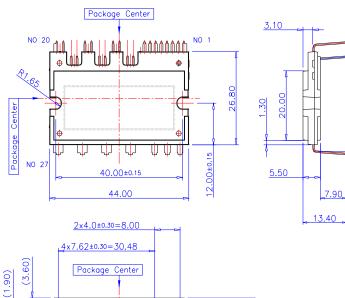
Figure 13. Typical Application Circuit

Detailed Package Outline Drawings

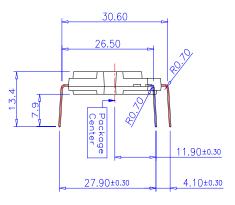


Lead Pitch : ±0.30

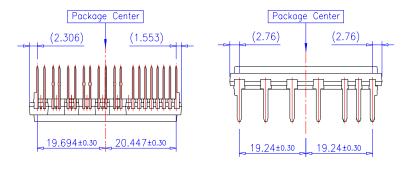
A: 1.778 B: 2.050 C: 2.531



Detailed Package Outline Drawings (Continued)

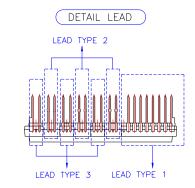


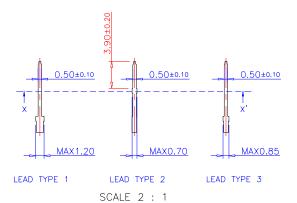
Lead Forming Dimension

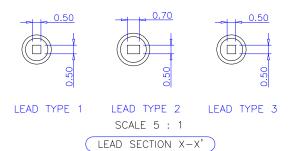


PKG Center to Lead Distance

Detailed Package Outline Drawings (Continued)











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